

Notice of References Cited	Application/Control No. 10/633,824	Applicant(s)/Patent Under Reexamination HE ET AL.	
	Examiner A. Sefer	Art Unit 2826	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0119103	06-2004	Thapar, Naresh	257/270
	B	US-2003/0022474	01-2003	Grover et al.	438/570
	C	US-2003/0207538	11-2003	Hshieh et al.	438/269
	D	US-4,903,189	02-1990	Ngo et al.	363/127
	E	US-2002/0134998	09-2002	Van Dalen et al.	257/213
	F	US-2003/0040144	02-2003	Blanchard et al.	438/145
	G	US-6,396,090	05-2002	Hsu et al.	257/242
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003-38760	03-2003	Japan	Kojima et al	
	O	JP 2002-334997	11-2002	Japan	Shimizu	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.